

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination LUK, TAI WAI | |
| | | Examiner | Art Unit | Page 1 of 1 |
| | | Leo T. Hinze | 2854 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-2004/0228219 A1 | 11-2004 | Miyahara et al. | 368/047 |
| * | B | US-6,414,908 B1 | 07-2002 | Kurasawa, Yoshimitsu | 368/80 |
| * | C | US-2004/0246821 A1 | 12-2004 | Fujisawa, Teruhiko | 368/204 |
| * | D | US-5,280,459 A | 01-1994 | Nakamura, Chiaki | 368/80 |
| * | E | US-6,643,223 B2 | 11-2003 | Fujisawa, Teruhiko | 368/204 |
| * | F | US-6,934,223 B2 | 08-2005 | Martin et al. | 368/204 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.